

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4	((("20020152046") or ("20070112538") or ("5083364") or ("6745094")).PN.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L2	1427	(702/57-59).CCLS.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L3	1241	(702/81-84).CCLS.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L4	1136	(702/89,108).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/11/22 14:22
L5	1259	(702/117).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/11/22 14:22
L6	773	(702/118,119).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/11/22 14:22
L7	918	(702/120,121,123,125).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/11/22 14:22
L8	1374	(324/73.1).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/11/22 14:22
L9	339	(324/500,537,754,765).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L10	63	(438/14,16,17).ccls. and parametric adj test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L11	115	(438/14,16,17).ccls. and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L12	1	(parametric and (test testing tested)).ti. and (load with wafer) same (automated or automatic\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22

L13	150	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with control	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L14	93	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with (controller controlling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L15	8	parametric adj test\$3 and (concurrent\$2 simultaneous\$2 synchronous\$2 multitasking) with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L16	0	parametric adj test\$3 and synchroniz\$3 with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L17	0	parametric adj test\$3 and synchronization with ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L18	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L19	1	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L20	4	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) probe) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L21	2	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near (data instrumentation instrument)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L22	0	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same initializ\$3 near file	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L23	6	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L24	6	parametric adj test\$3 and ((prepare adj wafer) (move adj wafer) (move adj probe)) same load near test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22

I.25	0	parametric adj test\$3 and ((wafer adj (loader positioner chuck)) (wafer adj tray adj loader) prober) same initializ\$3 near memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.26	3	parametric adj test\$3 and state adj oscillator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.27	2	state adj oscillator same fault-tolerant same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.28	2	state adj oscillator same fault-tolerant	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.29	34	state adj oscillator same test\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.30	2	state adj oscillator same state near module	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.31	0	state adj oscillator same state near object	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.32	10	state adj oscillator same control adj state	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.33	2	state adj oscillator same superstate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.34	3	((wafer adj electrical adj (test testing)) with (move moving movement))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.35	13	((semiconductor wafer) and (move moving movement prober alignment) with (simultaneous\$2 concurrent\$2) with (initialize initialized initialization))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
I.36	14	parametric adj test\$3 and concurrent adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22

L37	0	parametric adj test\$3 and simultaneous adj operation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L38	5	alignment with initialization with (concurrent\$2 simultaneous\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L39	51	("20020111775" "20020121915" "20020156548" "20030028343" "20030200513" "20030208340" "20030212469" "20030212523" "20040153979" "20040210413" "4896269" "5059899" "5078257" "5088045" "5177688" "5241266" "5360747" "5457400" "5483175" "5615138" "5726920" "5787190" "5806181" "5859964" "5869974" "5931952" "5943230" "5962862" "6113646" "6208904" "6240331" "6304095" "6314034" "6362013" "6370487" "6383825" "6420864" "6445199" "6462575" "6466314" "6486492" "6505138" "6507800" "6536006" "6567770" "6618682" "6624653" "6629282" "6639417" "6675138" "6785413").PN.	US-PGPUB; USPAT	OR	ON	2008/11/22 14:22
L40	4	((("20050021273") or ("6549863") or ("6563331") or ("6859760"))).PN.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L41	1883	state adj oscillator	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L42	714	state adj oscillator and control with state	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L43	380	state adj oscillator and control with state and (semiconductor wafer integrated adj circuit)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22

L44	76	fault adj tolerant with control with state	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/11/22 14:22
L45	1	("6119125").PN.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L46	1	("6124725").PN.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L47	2	((("5206582") or ("5726920")).PN.	US-PGPUB; USPAT	OR	OFF	2008/11/22 14:22
L48	5	("4012625" "5659483" "5742173" "7337088" "7383147").PN.	US-PGPUB; USPAT	OR	ON	2008/11/22 14:44

11/22/08 2:47:10 PM

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